



20th IEEE European Test Symposium

Cluj-Napoca, Romania

May 25 – 29, 2015

<http://www.ets15.ro>



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Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics and new trends in the area of electronic-based circuits and system testing. In 2015, ETS will take place in the Cluj-Napoca, Romania. It is organized by the Technical University of Cluj-Napoca, which co-sponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA). ETS also features a special track on Emerging Test Strategies (ETS²), where new problems and ideas can be discussed in an informal atmosphere. ETS is the major event of the European Test Week that includes TSS (Test Spring School) from May 22 to 25, and 3 workshops from May 28 to 29.

You are invited to participate and submit your contributions to ETS'15. The areas of interest include (but are not limited to) the following topics:

- Analog Test
- ATE Hardware and Software
- Automatic Test Generation
- Board Test and Diagnosis
- Boundary Scan Test
- Built-In Self-Test (BIST)
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability and Functional Safety
- Design for Test (DfT)
- Design for Manufacturing (DfM)
- Diagnosis and Silicon Debug
- Economics of Test
- Emerging Technologies
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- GPU Test
- High-Speed I/O Test
- Low-Power IC Test
- Memory Test and Repair
- MEMS Test
- Microprocessor Test
- Mixed-Signal Test
- Multi-/Many-core Processor Test
- Nanotechnology Test
- On-line Test
- Power Issues in Test
- Reconfigurable System Test
- Reliability
- RF Test
- Security and Trust Issues in Test
- Self-Repair
- Sensor Test
- Signal Integrity Test
- SiP, Stacked, 3D IC Test
- SoC Test
- Soft Errors
- Standards in Test
- System Test
- Test Compression
- Test Quality
- Test Synthesis
- Thermal Issues in Test
- Validation and Verification
- Variability Issues in Test
- Yield Analysis and Enhancement

Publications – ETS'15 will produce electronic formal proceedings - with ISBN number, and to be indexed in the IEEE Xplore digital library and other bibliographical search engines. In addition, the authors of the best contributions will be invited to submit an extended version of their paper to the "IEEE Design & Test of Computers Magazine" and to the Springer "Journal of Electronic Testing: Theory and Applications" (JETTA).

Submissions – ETS'15 seeks original, unpublished contributions of the following types:

- **Scientific papers** for the Formal Proceedings, presenting novel and complete research work
- **Contributions for the special track** on Emerging Test Strategies (ETS²)

ETS'15 also seeks proposals for:

- **Panels, embedded tutorials, and other special sessions**
- **Vendor presentations** focusing on new features of test related products
- **Fringe workshops**, to be held on May 28 and 29
- **Fringe meetings**, to be held during the European Test Week

Detailed submission instructions at: <http://www.ets15.ro>

- Key Dates:**
- Submission of title, abstract, authors: **December 15, 2014**
 - **PDF Uploading (extended):** **December 22, 2014 (SHARP!!)**
 - Notification of acceptance: **February 20, 2015**
 - Camera-ready manuscript: **March 20, 2015**

Further Information:

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